

FMV12N50E

FUJI POWER MOSFET

Super FAP-E³ series

N-CHANNEL SILICON POWER MOSFET

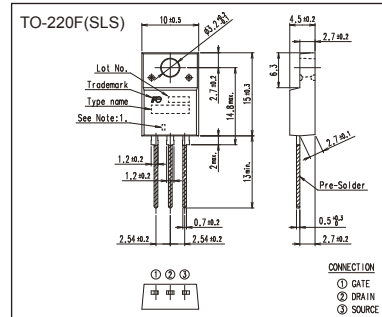
Features

- Maintains both low power loss and low noise
- Lower $R_{DS(on)}$ characteristic
- More controllable switching dv/dt by gate resistance
- Smaller V_{GS} ringing waveform during switching
- Narrow band of the gate threshold voltage ($3.0 \pm 0.5V$)
- High avalanche durability

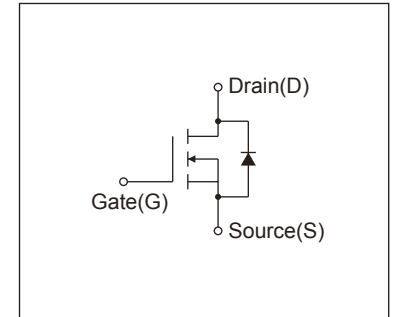
Applications

- Switching regulators
- UPS (Uninterruptible Power Supply)
- DC-DC converters

Outline Drawings [mm]



Equivalent circuit schematic



Maximum Ratings and Characteristics

Absolute Maximum Ratings at $T_c=25^\circ C$ (unless otherwise specified)

| Description | Symbol | Characteristics | Unit | Remarks |
|---|-----------|-----------------|-------------|-----------------------|
| Drain-Source Voltage | V_{DS} | 500 | V | |
| | V_{DSX} | 500 | V | $V_{GS} = -30V$ |
| Continuous Drain Current | I_D | ± 12 | A | |
| Pulsed Drain Current | I_{DP} | ± 48 | A | |
| Gate-Source Voltage | V_{GS} | ± 30 | V | |
| Repetitive and Non-Repetitive Maximum Avalanche Current | I_{AR} | 12 | A | Note*1 |
| Non-Repetitive Maximum Avalanche Energy | E_{AS} | 400 | mJ | Note*2 |
| Repetitive Maximum Avalanche Energy | E_{AR} | 6.0 | mJ | Note*3 |
| Peak Diode Recovery dV/dt | dV/dt | 6.5 | kV/ μs | Note*4 |
| Peak Diode Recovery $-di/dt$ | $-di/dt$ | 100 | A/ μs | Note*5 |
| Maximum Power Dissipation | P_D | 2.16 | W | $T_a=25^\circ C$ |
| | | 60 | | $T_c=25^\circ C$ |
| Operating and Storage Temperature range | T_{ch} | 150 | $^\circ C$ | |
| | T_{stg} | -55 to +150 | $^\circ C$ | |
| Isolation Voltage | V_{ISO} | 2 | kVrms | $t = 60sec, f = 60Hz$ |

Electrical Characteristics at $T_c=25^\circ C$ (unless otherwise specified)

| Description | Symbol | Conditions | min. | typ. | max. | Unit |
|----------------------------------|--------------|---|------|-------|------|----------|
| Drain-Source Breakdown Voltage | BV_{DSS} | $I_D=250\mu A, V_{GS}=0V$ | 500 | - | - | V |
| Gate Threshold Voltage | $V_{GS(th)}$ | $I_D=250\mu A, V_{DS}=V_{GS}$ | 2.5 | 3.0 | 3.5 | V |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS}=500V, V_{GS}=0V$ | - | - | 25 | μA |
| | | $V_{DS}=400V, V_{GS}=0V$ | - | - | 250 | |
| Gate-Source Leakage Current | I_{GSS} | $V_{GS}=\pm 30V, V_{DS}=0V$ | - | 10 | 100 | nA |
| Drain-Source On-State Resistance | $R_{DS(on)}$ | $I_D=6A, V_{GS}=10V$ | - | 0.444 | 0.52 | Ω |
| Forward Transconductance | g_{fs} | $I_D=6A, V_{DS}=25V$ | 6.5 | 13 | - | S |
| Input Capacitance | C_{iss} | $V_{DS}=25V$ | - | 1600 | 2400 | pF |
| Output Capacitance | C_{oss} | $V_{GS}=0V$ | - | 160 | 240 | |
| Reverse Transfer Capacitance | C_{rss} | $f=1MHz$ | - | 11.5 | 17.5 | |
| Turn-On Time | $t_d(on)$ | $V_{cc}=300V$ | - | 20 | 30 | ns |
| | t_r | $V_{GS}=10V$ | - | 9 | 13.5 | |
| Turn-Off Time | $t_d(off)$ | $I_D=6A$ | - | 100 | 150 | |
| | t_f | $R_G=15\Omega$ | - | 18 | 27 | |
| Total Gate Charge | Q_G | $V_{cc}=300V$ | - | 47 | 70.5 | nC |
| Gate-Source Charge | Q_{GS} | $I_D=12A$ | - | 10.5 | 16 | |
| Gate-Drain Charge | Q_{GD} | $V_{GS}=10V$ | - | 14 | 21 | |
| Avalanche Capability | I_{AV} | $L=2.12mH, T_{ch}=25^\circ C$ | 12 | - | - | A |
| Diode Forward On-Voltage | V_{SD} | $I_F=12A, V_{GS}=0V, T_{ch}=25^\circ C$ | - | 0.88 | 1.32 | V |
| Reverse Recovery Time | t_{rr} | $I_F=12A, V_{GS}=0V$ | - | 0.36 | - | μs |
| Reverse Recovery Charge | Q_{rr} | $-di/dt=100A/\mu s, T_{ch}=25^\circ C$ | - | 4.1 | - | μC |

Thermal Characteristics

| Description | Symbol | Test Conditions | min. | typ. | max. | Unit |
|--------------------|----------------|--------------------|------|------|-------|--------------|
| Thermal resistance | $R_{th(ch-c)}$ | Channel to Case | | | 2.083 | $^\circ C/W$ |
| | $R_{th(ch-a)}$ | Channel to Ambient | | | 58.0 | $^\circ C/W$ |

Note *1 : $T_{ch} \leq 150^\circ C$

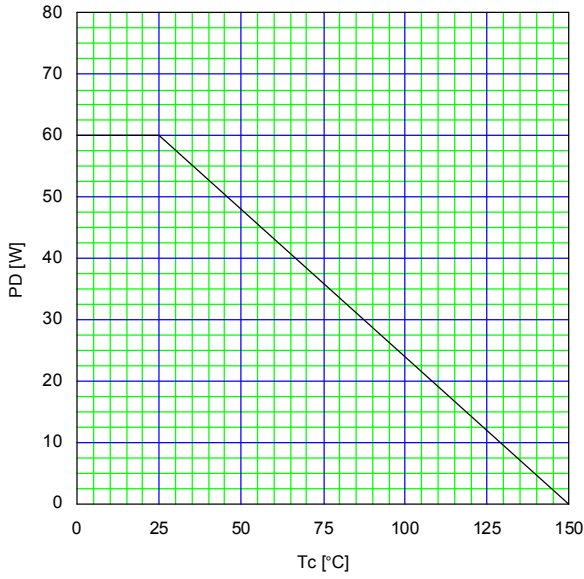
Note *2 : Stating $T_{ch}=25^\circ C, I_{AS}=5A, L=29.2mH, V_{CC}=50V, R_G=50\Omega$
 E_{AS} limited by maximum channel temperature and avalanche current.
 See to 'Avalanche Energy' graph.

Note *3 : Repetitive rating : Pulse width limited by maximum channel temperature.
 See to the 'Transient Thermal impedance' graph.

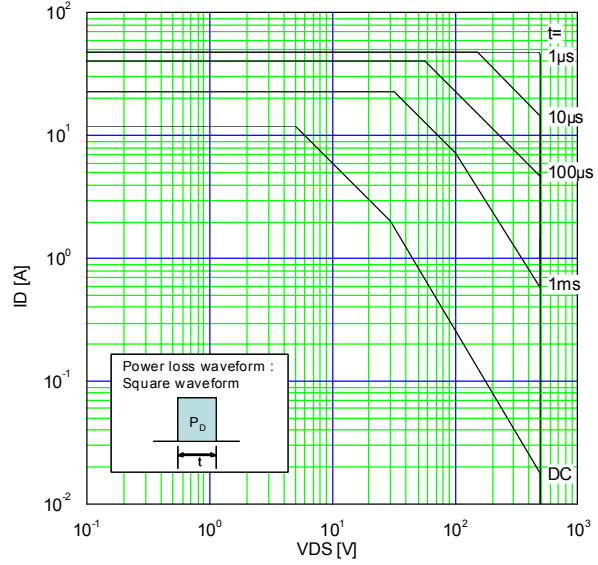
Note *4 : $I_F \leq I_D, -di/dt=100A/\mu s, V_{CC} \leq BV_{DSS}, T_{ch} \leq 150^\circ C$.

Note *5 : $I_F \leq I_D, dv/dt=6.5kV/\mu s, V_{CC} \leq BV_{DSS}, T_{ch} \leq 150^\circ C$.

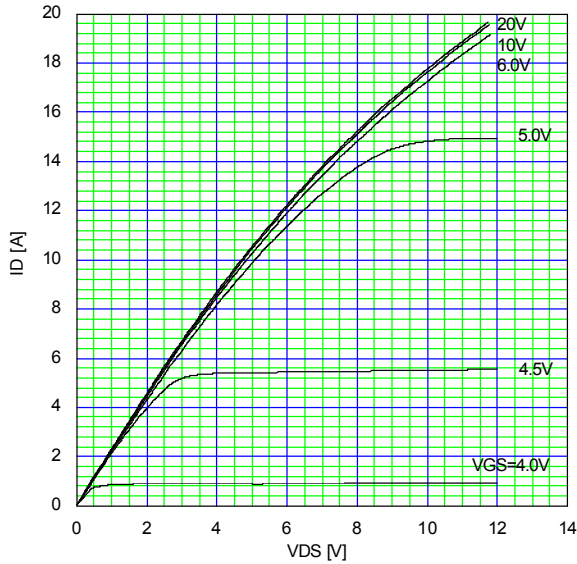
Allowable Power Dissipation
 $P_D = f(T_c)$



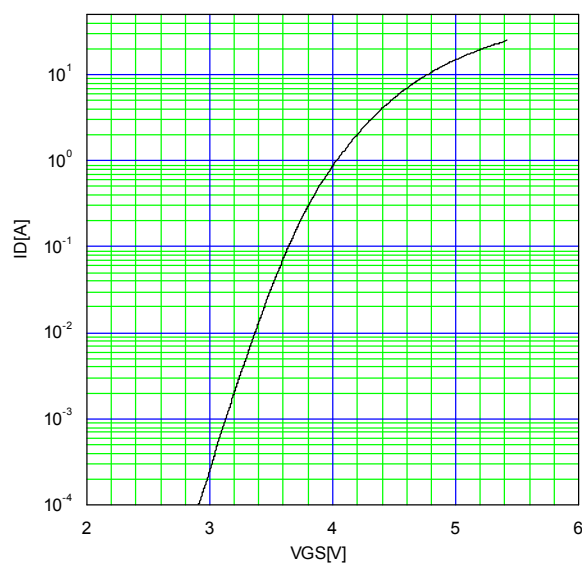
Safe Operating Area
 $I_D = f(V_{DS})$; Duty=0 (Single pulse), $T_c = 25^\circ\text{C}$



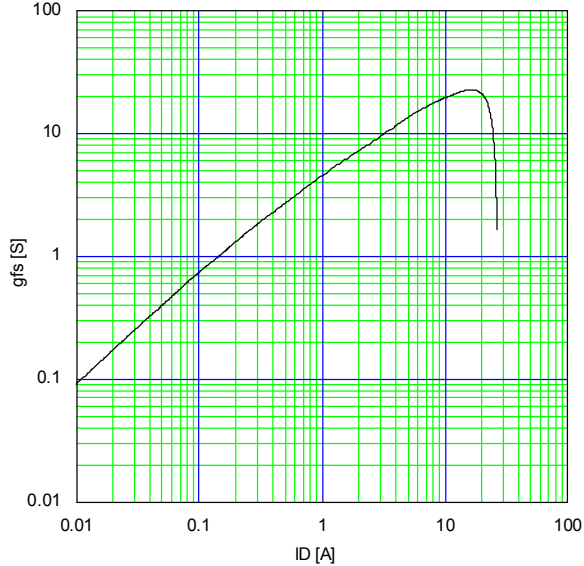
Typical Output Characteristics
 $I_D = f(V_{DS})$; 80 μs pulse test, $T_{ch} = 25^\circ\text{C}$



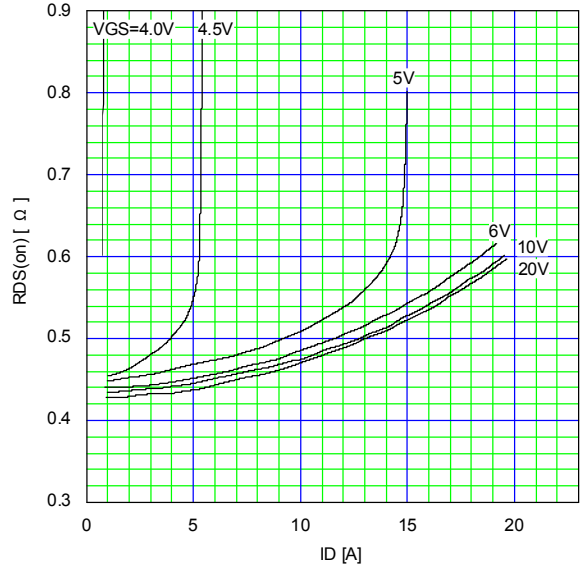
Typical Transfer Characteristic
 $I_D = f(V_{GS})$; 80 μs pulse test, $V_{DS} = 25\text{V}$, $T_{ch} = 25^\circ\text{C}$

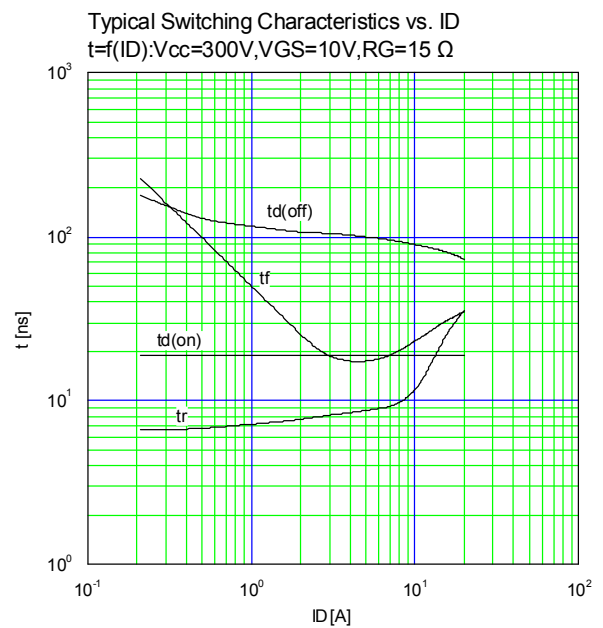
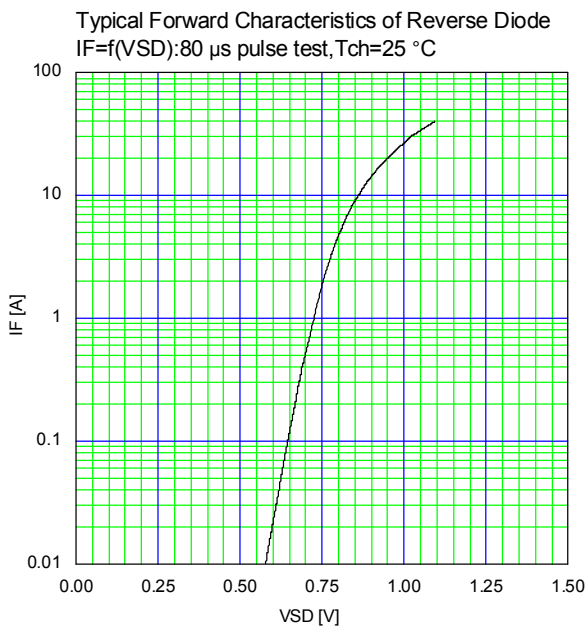
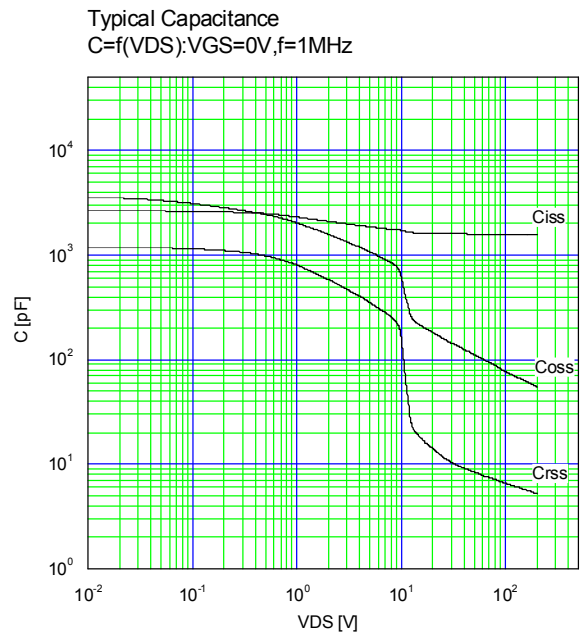
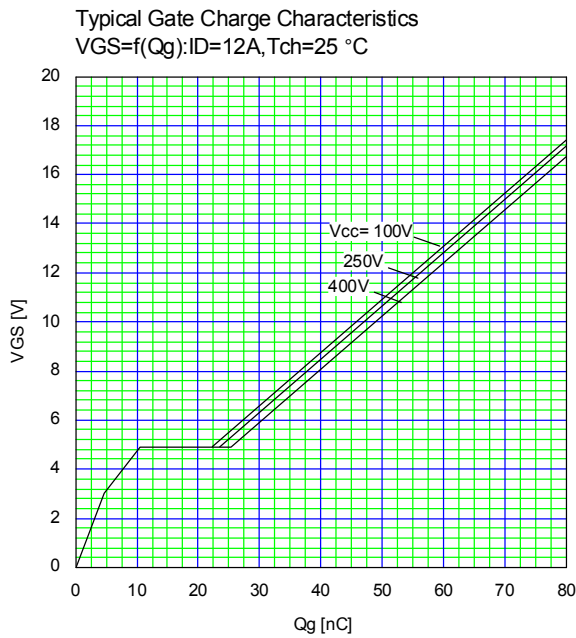
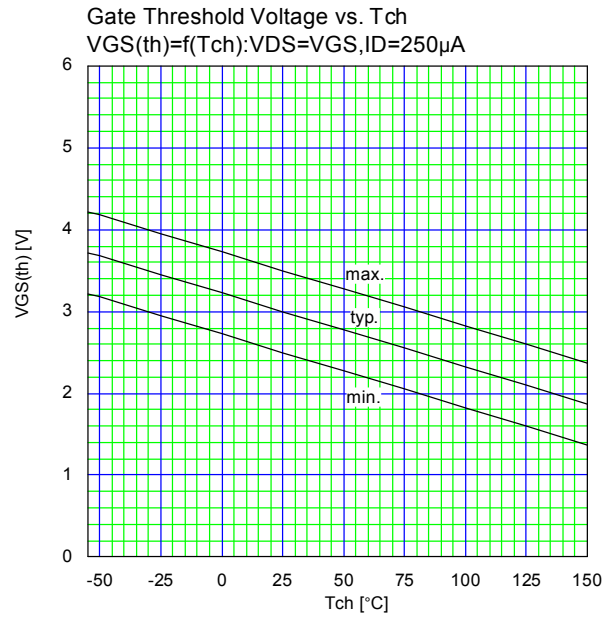
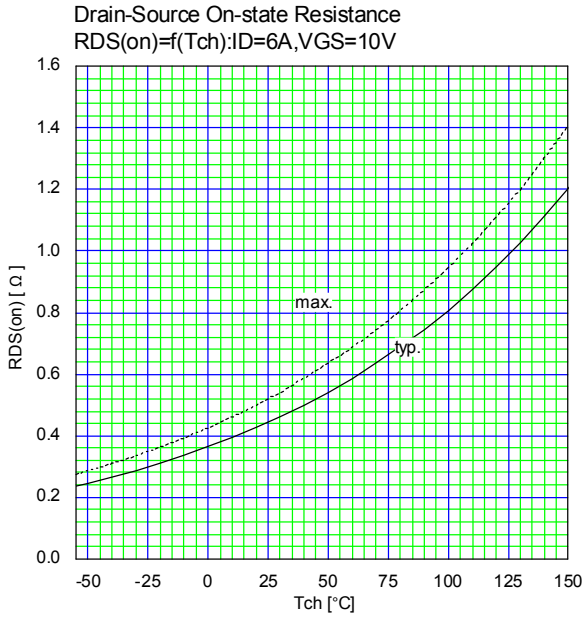


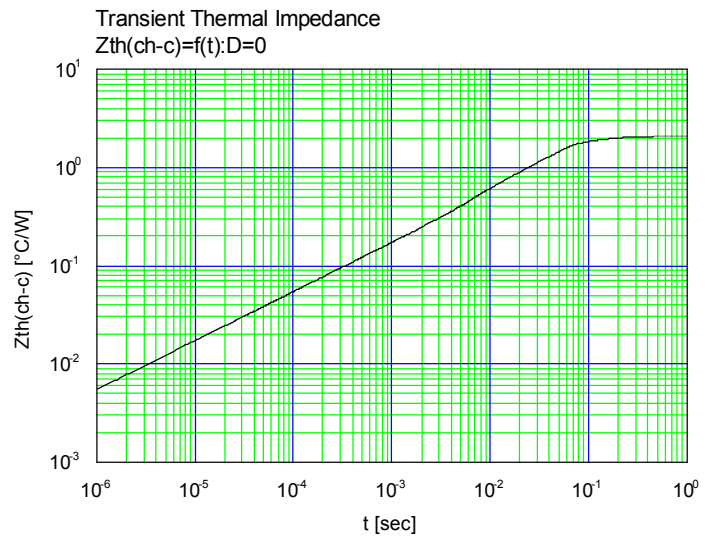
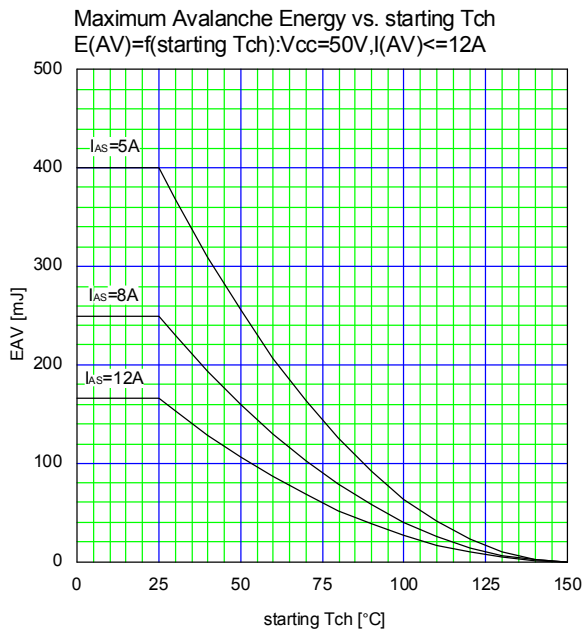
Typical Transconductance
 $g_{fs} = f(I_D)$; 80 μs pulse test, $V_{DS} = 25\text{V}$, $T_{ch} = 25^\circ\text{C}$



Typical Drain-Source on-state Resistance
 $R_{DS(on)} = f(I_D)$; 80 μs pulse test, $T_{ch} = 25^\circ\text{C}$







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